



REPORT No. : SZ17080187E01

FCC TEST REPORT

APPLICANT : Anker Technology Co., Limited

PRODUCT NAME : Nebula Mars Lite

MODEL NAME : D2321

TRADE NAME : Nebula

BRAND NAME : N/A

FCC ID : 2AB7K-D2321

STANDARD(S) : 47 CFR Part 15 Subpart B

TEST DATE : 2017-08-25 to 2017-09-07

ISSUE DATE : 2017-09-12

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

NOTE: This document is issued by MORLAB, the test report shall not be reproduced except in full without prior written permission of the company. The test results apply only to the particular sample(s) tested and to the specific tests carried out which is available on request for validation and information confirmed at our website.



DIRECTORY

1. TECHNICAL INFORMATION	5
1.1. APPLICANT INFORMATION	5
1.2. EQUIPMENT UNDER TEST (EUT) DESCRIPTION	5
2. TEST RESULTS	7
2.1. APPLIED REFERENCE DOCUMENTS	7
3. TEST CONDITIONS SETTING	8
3.1. TEST MODE	8
3.2. TEST SETUP AND EQUIPMENTS LIST	9
3.2.1. CONDUCTED EMISSION	9
3.2.2. RADIATED EMISSION	11
4. 47 CFR PART 15B REQUIREMENTS	13
4.1. CONDUCTED EMISSION	13
4.1.1. REQUIREMENT	13
4.1.2. TEST DESCRIPTION	13
4.1.3. TEST RESULT	13
4.2. RADIATED EMISSION	16
4.2.1. REQUIREMENT	16
4.2.2. TEST DESCRIPTION	16
4.2.3. FREQUENCY RANGE OF MEASUREMENT	16
4.2.4. TEST RESULT	17
ANNEX A TEST SETUP PHOTOS	20
ANNEX B TEST UNCERTAINTY	22
ANNEX C TESTING LABORATORY INFORMATION	23



- 1. IDENTIFICATION OF THE RESPONSIBLE TESTING LABORATORY23
- 2. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION.....23
- 3. ACCREDITATION CERTIFICATE23
- 4. TEST ENVIRONMENT CONDITIONS23

Change History		
Issue	Date	Reason for change
1.0	2017-09-12	First edition



Test Report Declaration

Applicant	Anker Technology Co., Limited
Applicant Address	Room 1318-19,Hollywood Plaza,610 Nathan Road, Mongkok, Kowloon,Hong Kong
Manufacturer	Anker Technology Co., Limited
Manufacturer Address	Room 1318-19,Hollywood Plaza,610 Nathan Road, Mongkok, Kowloon,Hong Kong
Product Name	Nebula Mars Lite
Model Name	D2321
Brand Name	N/A
HW Version	9893C
SW Version	N/A
Test Standards	47 CFR Part 15 Subpart B
Test Result	PASS

Tested by : Mo Yugai
Mo Yugai (Test Engineer)

Approved by : Andy Yeh
Andy Yeh (Technology Director)



1. Technical Information

Note: Provided by applicant

1.1. Applicant Information

Company: Anker Technology Co., Limited
Address: Room 1318-19, Hollywood Plaza, 610 Nathan Road, Mongkok, Kowloon, Hong Kong

1.2. Equipment under Test (EUT) Description

EUT Type:	Nebula Mars Lite
Serial No:	(N/A, marked #1 by test site)
Hardware Version:	9893C
Software Version:	N/A

Power supply:	Battery	
	Brand Name:	FUJI
	Model No.:	BT-H003
	Serial No.:	(N/A, marked #1 by test site)
	Capacity:	3350mAh
	Rated Voltage:	14.52V
	Charge Limit:	16.8V
Ancillary Equipment :	AC Adapter (Charger for Battery)	
	Brand Name:	N/A
	Model No.:	NSA60ED-190300
	Serial No.:	(N/A, marked #1 by test site)
	Rated Input:	~ 100-240V, 50/60Hz, 1.5A max
	Rated Output:	≡ 19V, 3A

NOTE:

1. The EUT is a Nebula Mars Lite which supports ISM 2.4GHz Bluetooth band and WIFI (802.11a/b/g/n) band.
2. The EUT is equipped with a USB port, a HDMI port and an AUDIO OUT port which can be connected to ancillary equipments.



REPORT No. : SZ17080187E01

3. For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	2017.08.29	PASS
2	15.109	Radiated Emission	2017.09.01	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



3. Test Conditions Setting

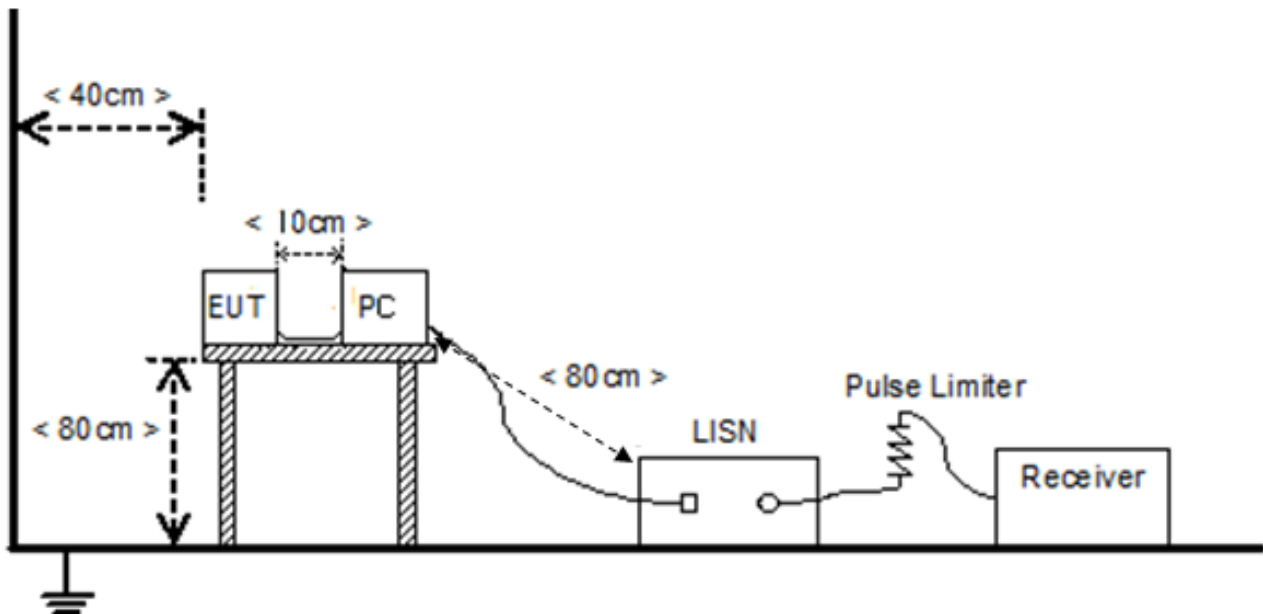
3.1. Test Mode

1	<p>The first test mode</p> <p>The EUT configuration of the immunity tests is EUT + Battery + Adapter + PC + U-Dish + Remote Control + Earphone.</p> <p>In this test mode, the EUT was connected to the Adapter, a PC, a U-Dish and an Earphone and charged by the Adapter, meanwhile, the EUT was working normally as an intentional device.</p>
---	---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------

3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu\text{H}$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity is maintained with respect to the impedance characteristics as prescribed in ANSI C63.4-2014 at Clause 4.3.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2017.05.17	2018.05.16
LISN	Schwarzbeck	NSLK 8127	812744	2017.05.17	2018.05.16
Pulse Limiter (20dB)	VTSD	9561D	9537	2017.05.17	2018.05.16
PC	Lenovo	ThinkPad T430i	0B68192JS	N/A	N/A



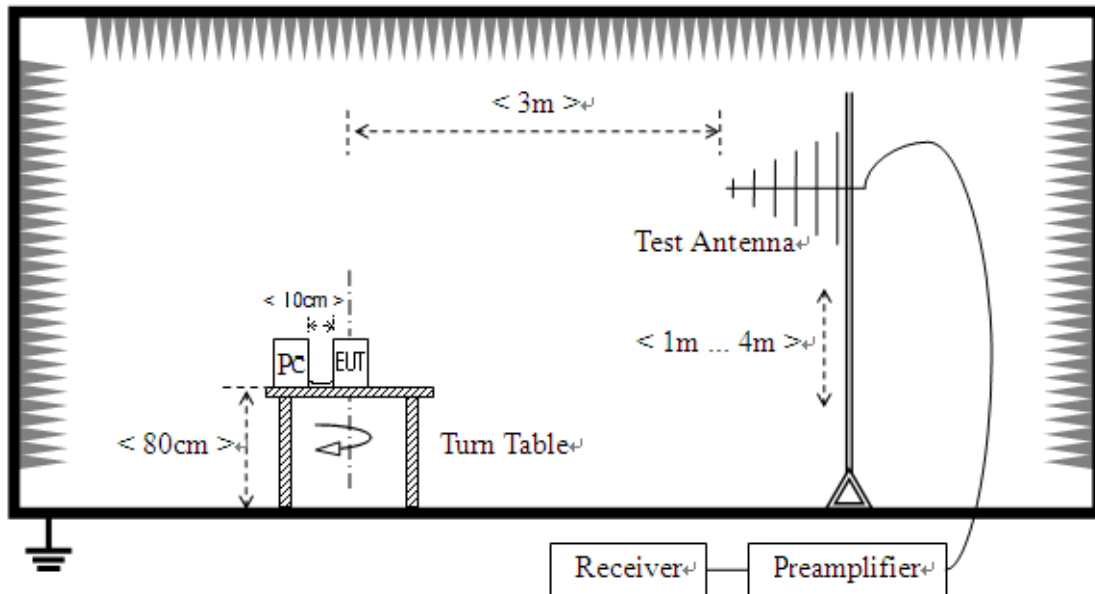
C. Test Software Utilized

Model	Version Number	Producer
TS+ -[JS32-CE]	Version2.5.0.0	Tonscend

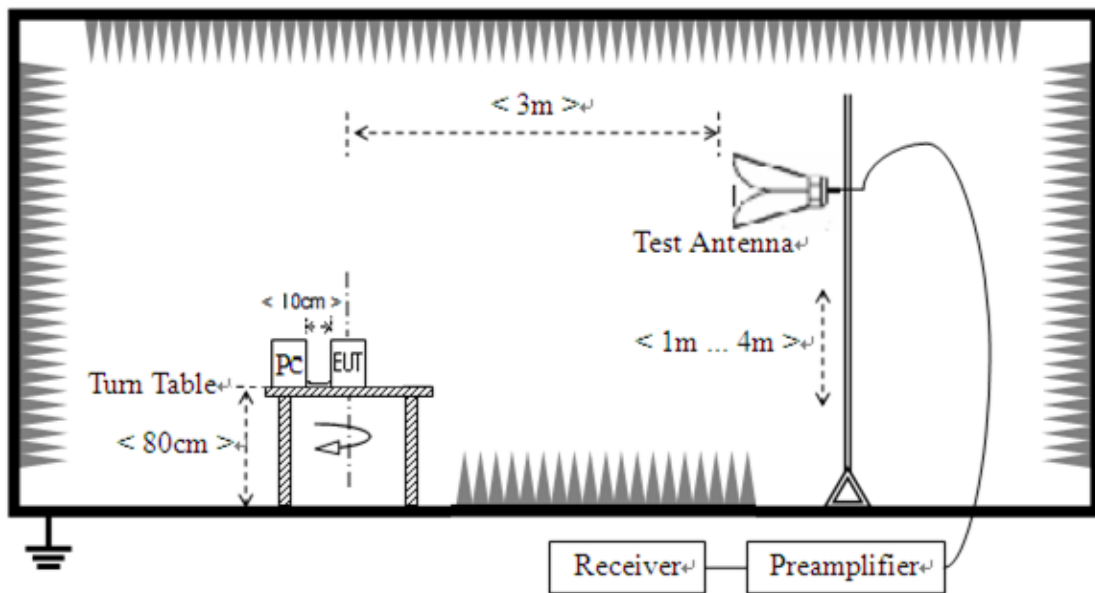
3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of



the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
MXE EMI Receiver	Agilent	N9038A	MY54130016	2017.05.17	2018.05.16
Semi-Anechoic Chamber	Changning	9m*6m*6m	N/A	2017.01.11	2018.01.10
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2016.12.09	2017.12.08
Test Antenna - Horn	Schwarzbeck	BBHA9120C	9120C-384	2017.03.30	2018.03.29
18-26.5GHz pre-Amplifier	MA03	TS-PR18	Rohde&Schwarz	2017.05.17	2018.05.16
26.5-40GHz pre-Amplifier	C00990	NSP4000-SP2	Miteq	2017.05.17	2018.05.16
PC	Lenovo	ThinkPad T430i	0B68192JS	N/A	N/A

C. Test Software Utilized

Model	Version Number	Producer
MORLAB EMCR V1.2	Version 1.0	MORLAB

4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50 μ H/50 Ω line impedance stabilization network (LISN).

Frequency range (MHz)	Conducted Limit (dB μ V)	
	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- The limit subjects to the Class B digital device.
- The lower limit shall apply at the band edges.
- The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

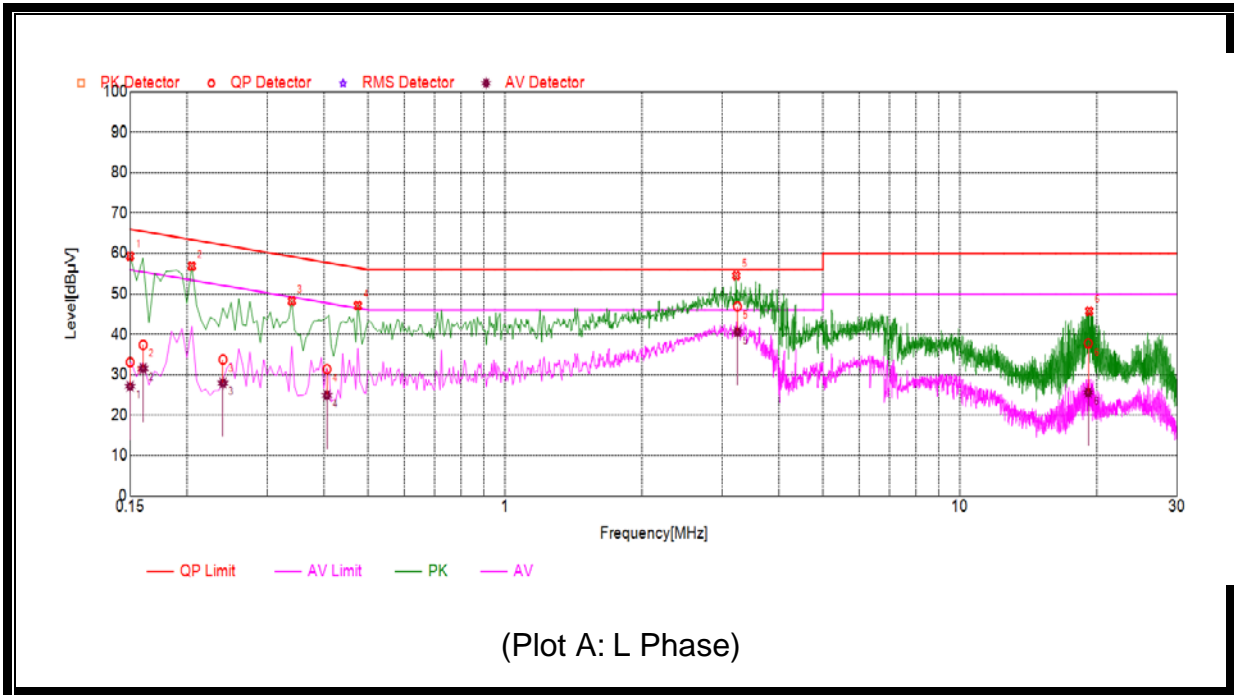
4.1.2. Test Description

See section 3.2.1 of this report.

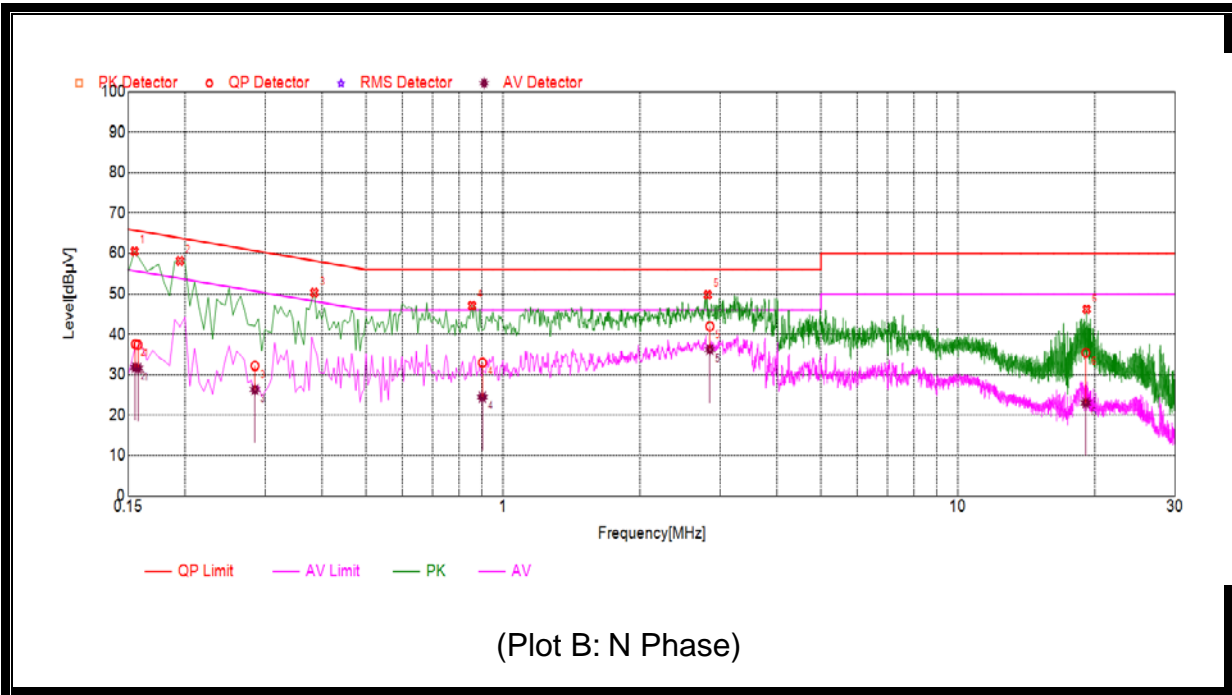
4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

A. Test Plot and Suspicious Points:



No.	Fre. (MHz)	Emission Level (dBµV)		Limit (dBµV)		Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	33.11	27.12	66.00	56.00	Line	PASS
2	0.1602	37.41	31.56	65.45	55.45		PASS
3	0.24	33.75	27.93	62.10	52.10		PASS
4	0.4062	31.38	24.89	57.73	47.73		PASS
5	3.2432	46.90	40.62	56.00	46.00		PASS
6	19.150	37.77	25.60	60.00	50.00		PASS



No.	Fre. (MHz)	Emission Level (dBµV)		Limit (dBµV)		Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.1576	37.46	31.62	65.59	55.59	Neutral	PASS
2	0.1556	37.59	31.80	65.70	55.70		PASS
3	0.285	32.20	26.33	60.67	50.67		PASS
4	0.9012	32.99	24.47	56.00	46.00		PASS
5	2.85	41.97	36.22	56.00	46.00		PASS
6	19.108	35.46	23.04	60.00	50.00		PASS

Result: Pass



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109 (a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency range (MHz)	Field Strength Limitation at 3m Measurement Dist	
	($\mu\text{V}/\text{m}$)	($\text{dB}\mu\text{V}/\text{m}$)
30.0 - 88.0	100	20log 100
88.0 - 216.0	150	20log 150
216.0 - 960.0	200	20log 200
Above 960.0	500	20log 500

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in $\text{dB}\mu\text{V}/\text{m}$ is calculated by $20\log$ Emission Level($\mu\text{V}/\text{m}$).

4.2.2. Test Description

See section 3.2.2 of this report.

4.2.3. Frequency range of measurement

According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:



Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
Below 1.705	30.
1.705-108	1000.
108-500	2000.
500-1000	5000.
Above 1000	5th harmonic of the highest frequency or 40 GHz, whichever is lower.

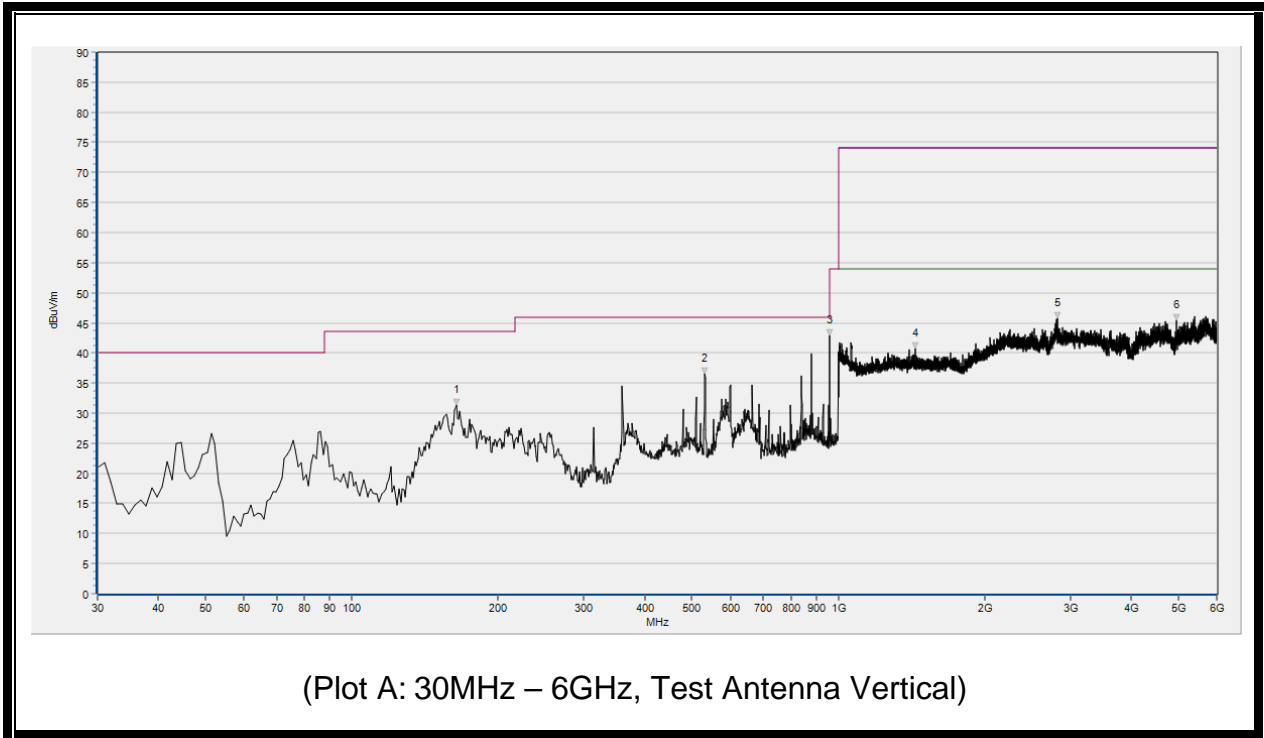
4.2.4. Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

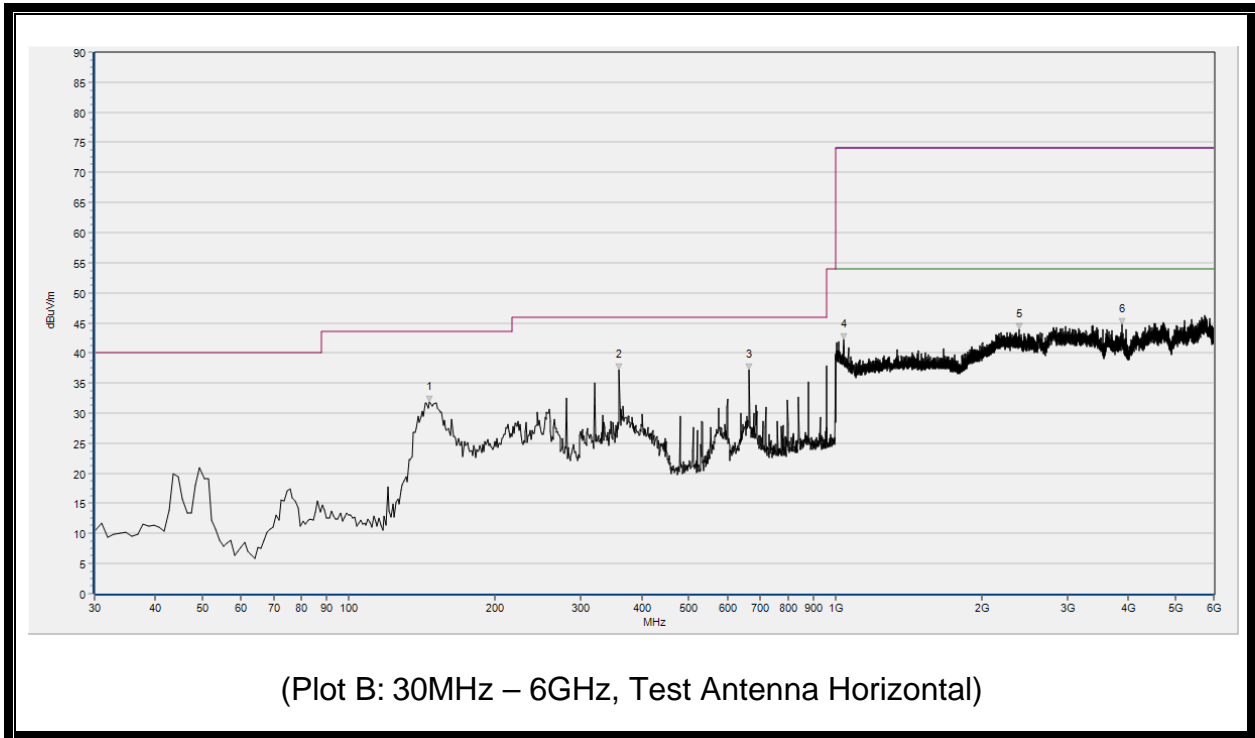
The amplitude of spurious emissions (6GHz-30GHz) which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

A. Test Plots and Suspicious Points:



No.	Fre. MHz	Pk dBµV/m	QP dBµV/m	AV dBµV/m	Limit-PK dBµV/m	Limit-QP dBµV/m	Limit-AV dBµV/m	ANT	Verdict
1	163.860	N.A.	31.27	N.A.	N.A.	43.50	N.A.	V	PASS
2	531.490	N.A.	36.51	N.A.	N.A.	46.00	N.A.	V	PASS
3	960.230	N.A.	42.99	N.A.	N.A.	54.00	N.A.	V	PASS
4	1440.000	40.69	N.A.	32.58	74.00	N.A.	54.00	V	PASS
5	2820.520	45.68	N.A.	39.02	74.00	N.A.	54.00	V	PASS
6	4953.200	45.46	N.A.	38.77	74.00	N.A.	54.00	V	PASS



No.	Fre. MHz	Pk dBµV/m	QP dBµV/m	AV dBµV/m	Limit-PK dBµV/m	Limit-QP dBµV/m	Limit-AV dBµV/m	ANT	Verdict
1	146.400	N.A.	31.82	N.A.	N.A.	43.50	N.A.	H	PASS
2	359.800	N.A.	37.19	N.A.	N.A.	46.00	N.A.	H	PASS
3	665.350	N.A.	37.23	N.A.	N.A.	46.00	N.A.	H	PASS
4	1040.000	42.30	N.A.	35.09	74.00	N.A.	54.00	H	PASS
5	2388.800	43.83	N.A.	36.11	74.00	N.A.	54.00	H	PASS
6	3881.680	44.83	N.A.	37.61	74.00	N.A.	54.00	H	PASS

Result: Pass

Annex A Test Setup Photos

1. Conducted emission main's port front view



2. Conducted emission main's port side view



3. Radiated emission (30MHz-1GHz)



4. Radiated emission (above 1GHz)





Annex B Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	$\pm 1.8\text{dB}$
Uncertainty of Radiated Emission:	$\pm 3.1\text{dB}$



Annex C Testing Laboratory Information

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: The FCC designation number is CN1192.
(Shenzhen Morlab Communications Technology Co., Ltd.)

4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

***** END OF REPORT *****